

The background of the slide is a grayscale scanning electron microscope (SEM) image showing a surface with a granular, porous, or crystalline texture. In the top-left corner, there is a solid purple horizontal bar.

Dielectric Measurements on Thin Film (LiNbO₃; SiPt)

Physics Advanced Labs by Professor António Onofre

Britta Dorn

Marco Brito

Rafael Cerqueira

Outline



Introduction- Know how to produce and study thin films



Mathematical details- What we need to know for dielectric data analysis

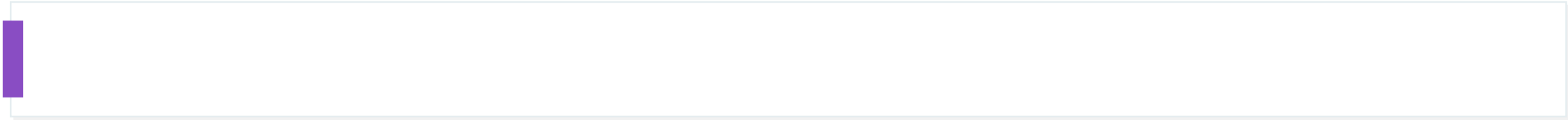


Data analysis- Learn to fit in Origin in physical analysis context



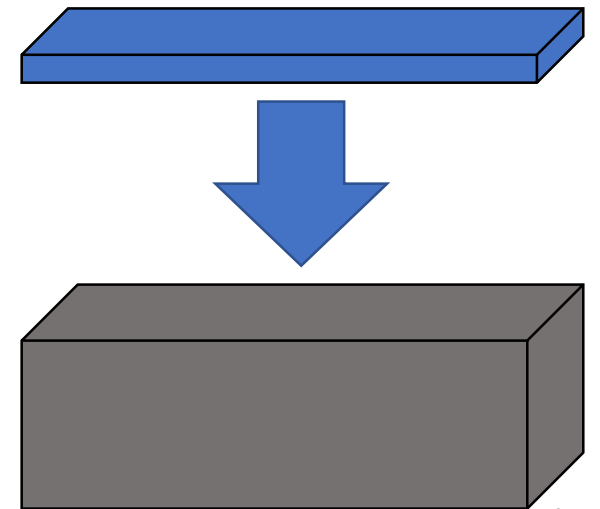
Discussion and conclusion

Introduction



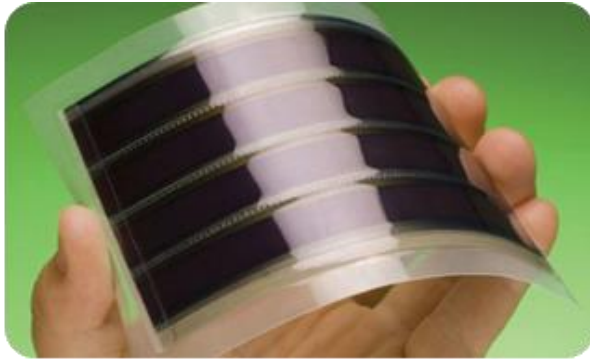
Thin Films

- In the past, present and in future we have used and will use thin films in our daily life from low to high tech devices.
- What is a thin film? It is a set of atomic layers (in the order of nanometers) that are deposited on a substrate. Due to tensile or epitaxial strains we can change the different physical properties of the materials.
- The positive aspect of this is, we can have the following:
 - Small Size;
 - Economic value;
 - Functionality;



Utilities and applications

Solar cells;



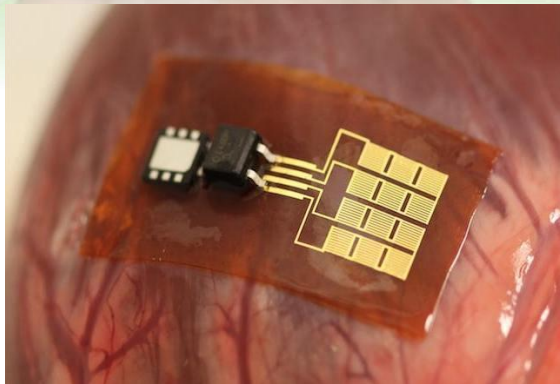
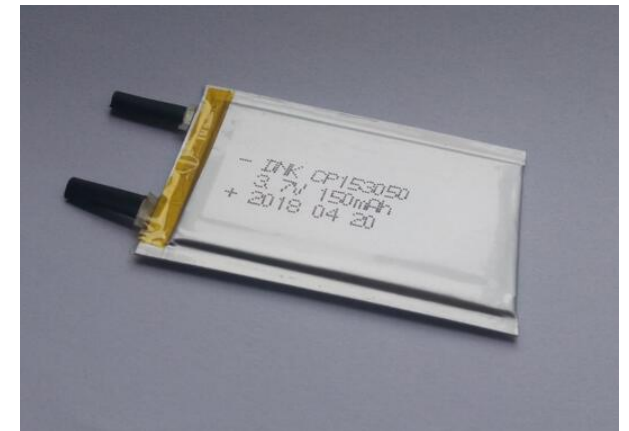
Glasses



Sem anti-reflexo

Com anti-reflexo

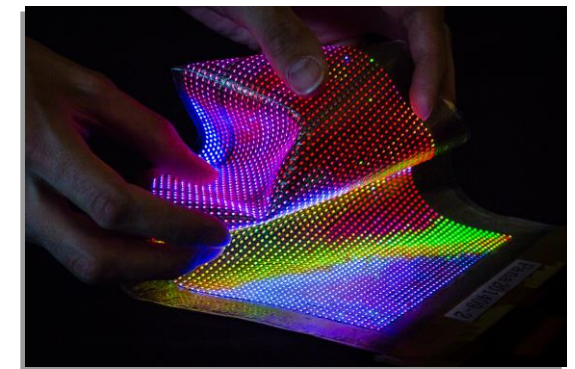
Batteries



Medical Devices



Hard disk

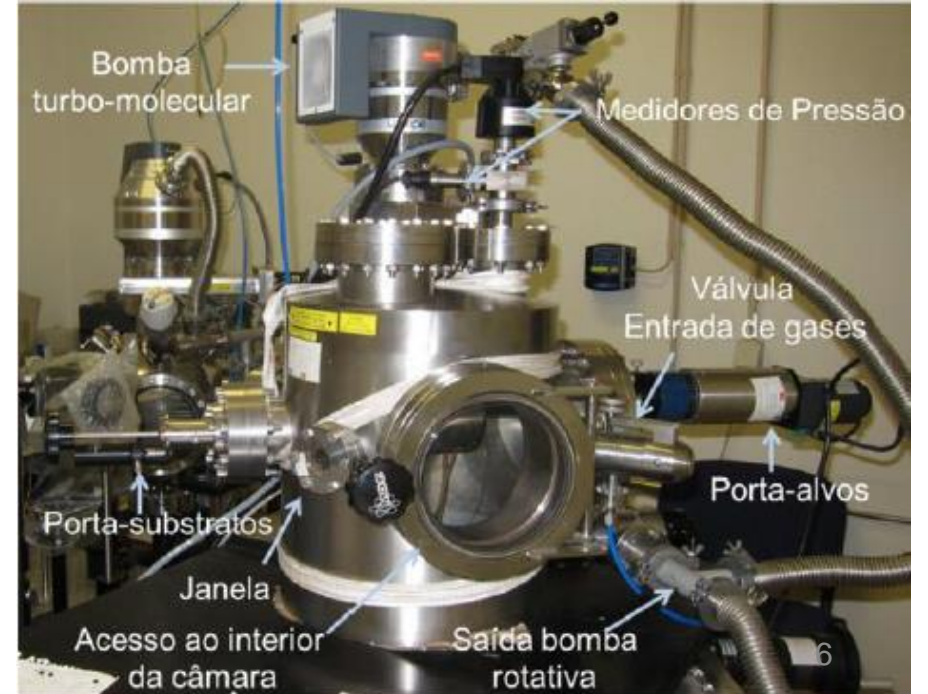
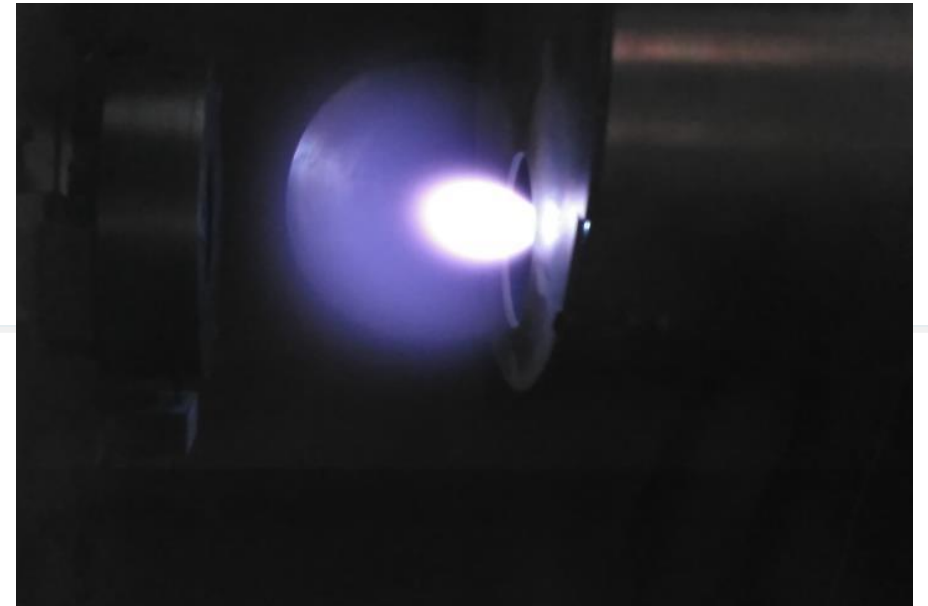
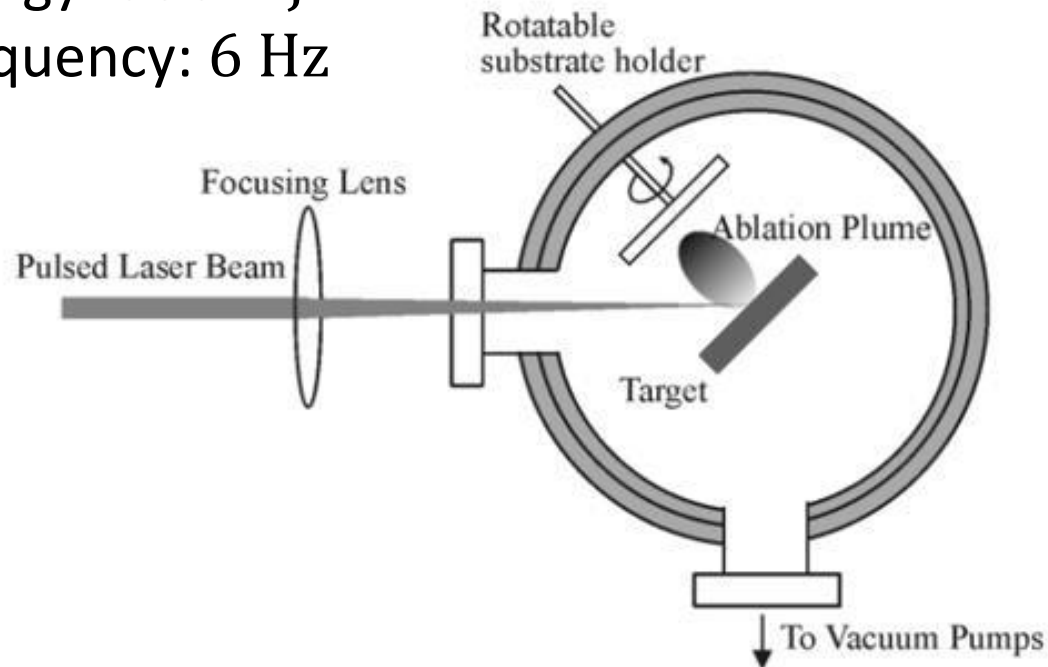


Screens

PLD- How to produce?

Experimental conditions:

- Deposition Temperature: 650°C
- O₂ Pressure: 1mbar
- Deposition Time: 45 minutes
- Laser Energy: 350 mJ
- Laser Frequency: 6 Hz



LiNbO₃

- Professor Bernardo and his PhD students Bruna and João wanted to make thin films and study their physical properties.
- They chose LiNbO₃ as a film and PtSi(001) as substrate due to the wide range of physical properties exhibited by LiNbO₃.

LiNbO3 ID Card

- Physical properties: ferroelectric material, high piezoelectric, pyroelectric, electro-optical, birefringent, photorefractive and photoelastic properties.
- Structure: rhombohedral (R3c)
- Lattice parameters: $a = 5,1494 \text{ \AA}$ and $c = 13,862 \text{ \AA}$
- Currie Temperature: 1,530K
- Molar Mass: 147,846 g/mol
- Band Gap: 4eV

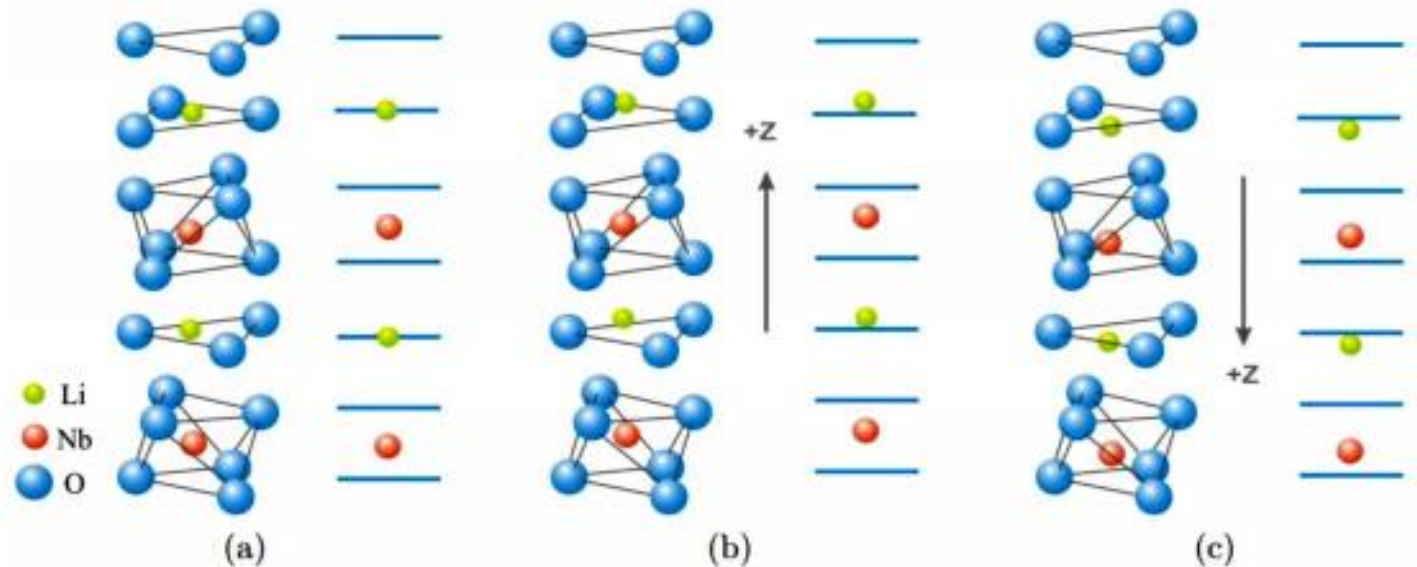
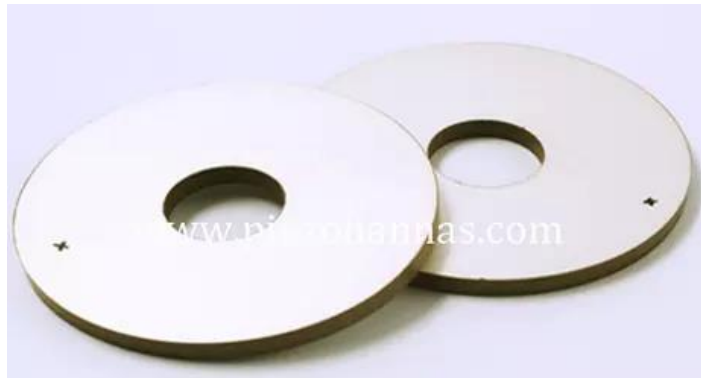


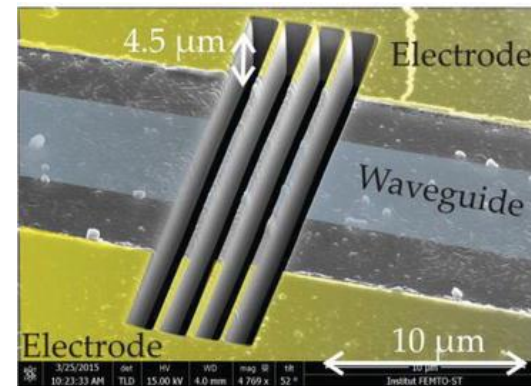
Figure 1: Atomic structure of LiNbO₃ in (a) paraelectric phase and (b, c) ferroelectric phases[2].

LiNbO₃- Utilities and applications

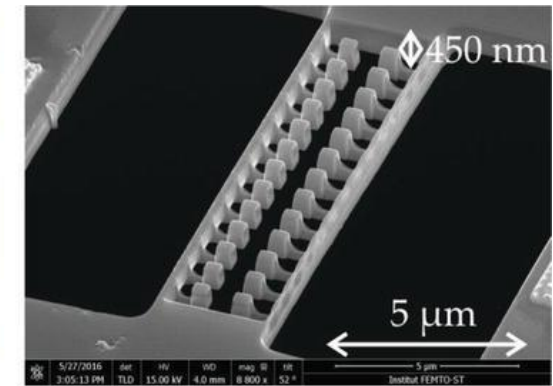
- Piezoelectric Devices



Waveguides



(a)

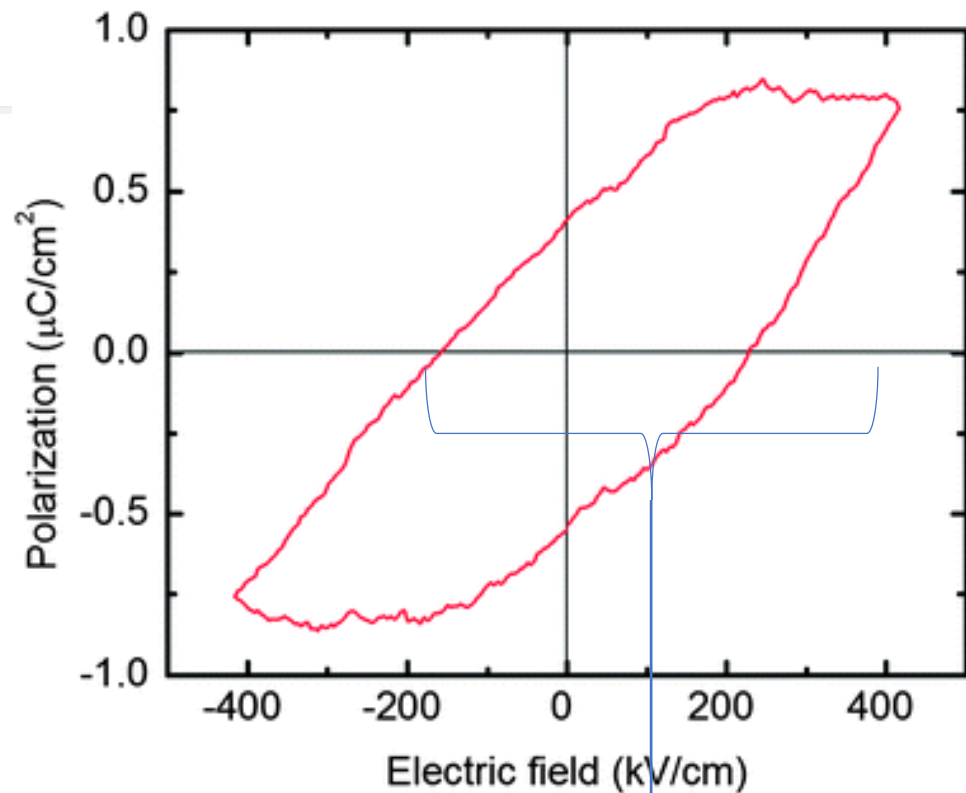


(b)

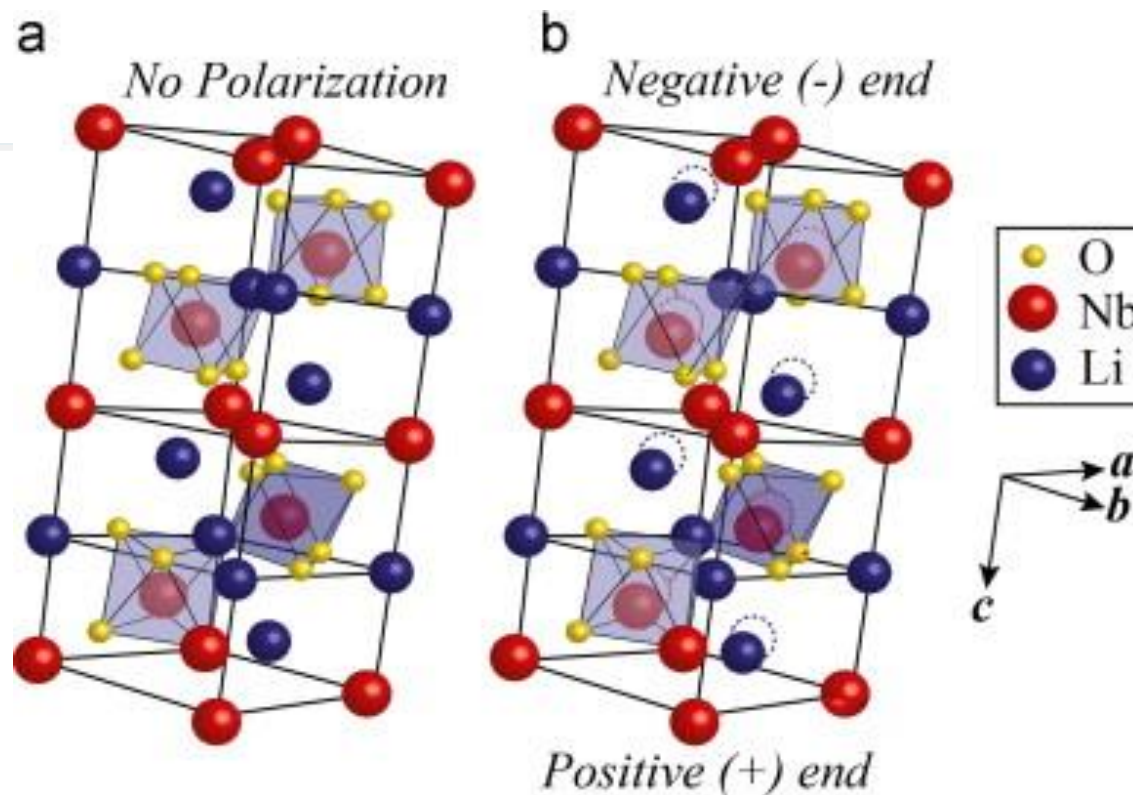


Optical Modulators

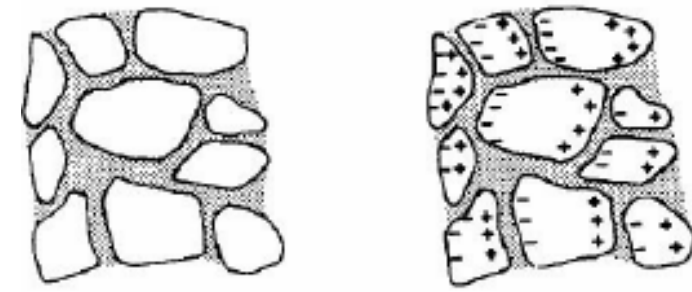
Ferroelectric Effect



Relaxion Time



How to measure dielectric data?



Various polarization processes.

- To know better the electric properties we need to measure the dielectric data with an impedance analyser.

Impedance analyzer:

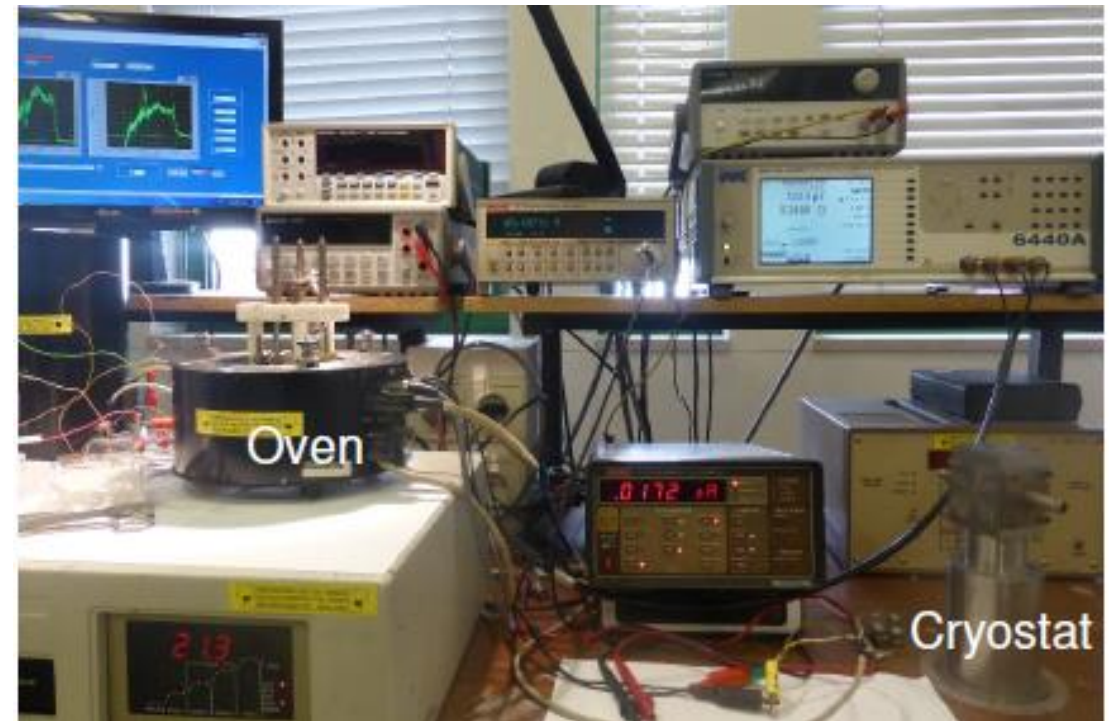
- Waine Kerr 6440 A;
- frequency range:10Hz - 3MHz;

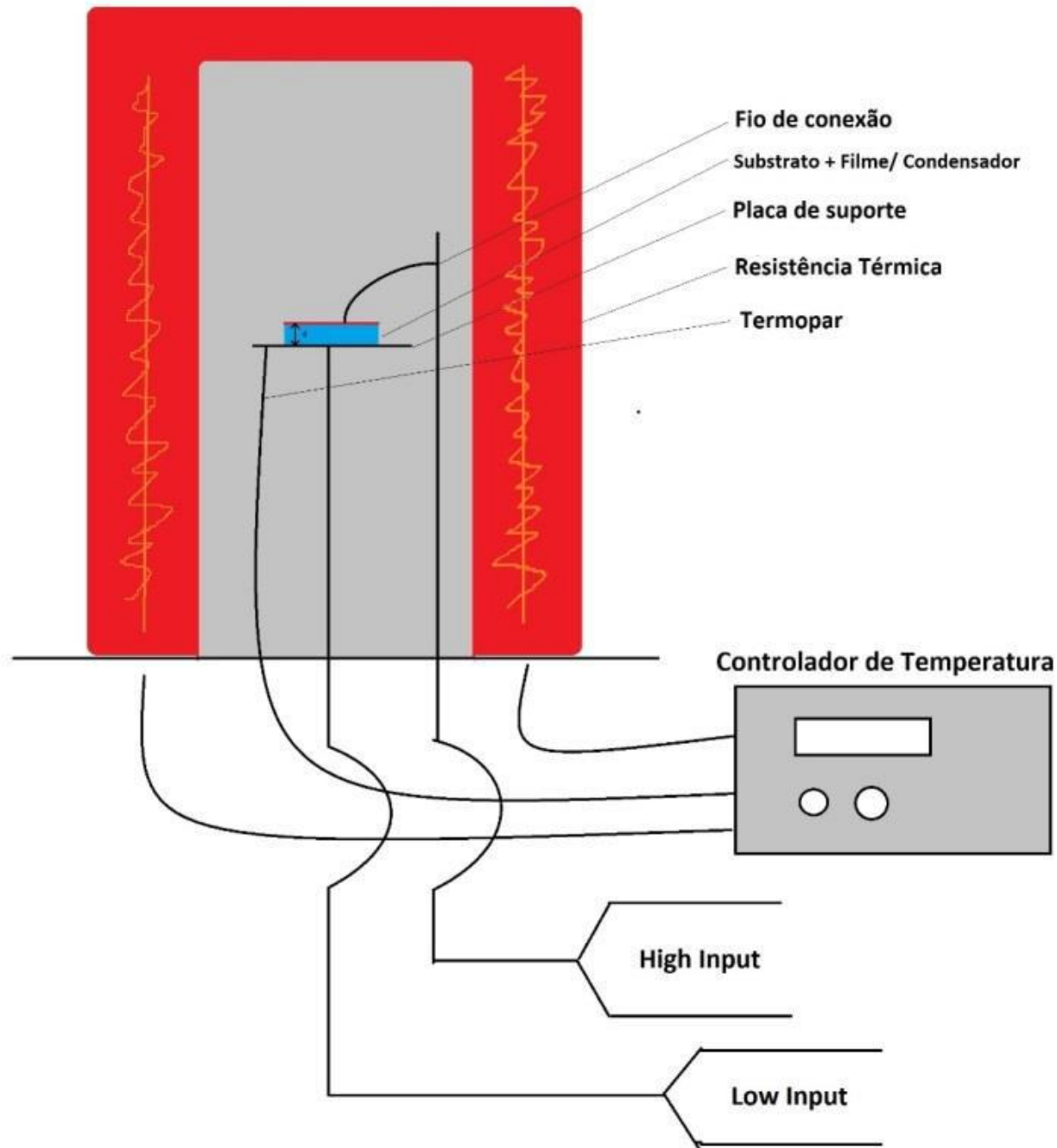
Temperature controller and furnace:

- Polymer Labs PL706 PID;
- temperatures of 15 – 200°C (50°C in our case);
- 2°C/min temperature measurement;

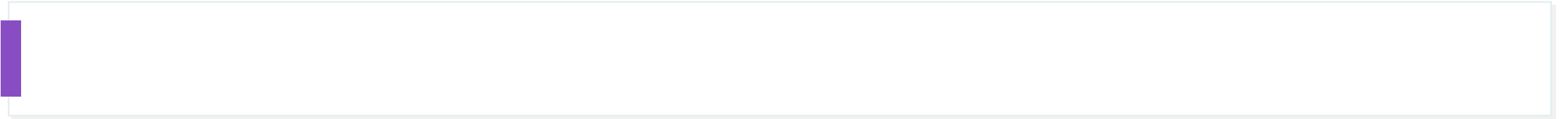
Software:

- Labview;





Mathematical details



Dielectric function

- The susceptibility of a material is a measure of the electrical polarizability of the said material. For example in linear dielectrics, the polarization is given by: $\mathbf{P} = \epsilon_0 \chi \mathbf{E}$.
- The electric displacement field which describes the field produced by free charges is given by: $\mathbf{D} = \epsilon_0 \mathbf{E} + \mathbf{P} = \epsilon_0 (\mathbf{E} + \chi \mathbf{E}) = \epsilon_0 (1 + \chi) \mathbf{E}$.
- The permittivity of a material is then: $\epsilon = \epsilon_0 (1 + \chi)$.
- The dielectric function is defined as $\epsilon_r = \frac{\epsilon}{\epsilon_0}$.

Dielectric function

- For example in the vacuum the dielectric function is $\epsilon_r = \frac{\epsilon}{\epsilon_0} = \frac{\epsilon_0}{\epsilon_0} = 1$ while for other materials is >1 .
- For nonlinear materials and anisotropic materials the dielectric function might be a highly nonlinear equation and dependent on the frequency of the electric field and might not be a scalar but a tensor.
- There are several models for the dielectric functions of a material.

Havriliak-Negami model

- In this model the dielectric function is given by $\epsilon(\omega) = \epsilon_{\infty} + \frac{\Delta\epsilon}{(1 + (i\omega\tau_{HN})^{\alpha})^{\beta}}$
- It can be divided in its real and imaginary parts given by

$$\Re(\epsilon) = \epsilon' = \Delta\epsilon r(\omega) \cos[\gamma\psi(\omega)] + \epsilon_{\infty}; \quad \Im(\epsilon) = \epsilon'' = \Delta\epsilon r(\omega) \sin[\gamma\psi(\omega)]$$

where

$$r(\omega) = \left[1 + 2 (\omega\tau_{HN})^{\beta} \cos\left(\frac{\beta\pi}{2}\right) + (\omega\tau_{HN})^{2\beta} \right]^{-\gamma/2}$$

$$\psi(\omega) = \arctan \left[\frac{\sin(\beta\pi/2)}{(\omega\tau_{HN})^{-\beta} + \cos(\beta\pi/2)} \right]$$

Havriliak-Negami model

- Moreover it is known that the dielectric function is dependent of some experimental parameters

$$\epsilon' = \frac{C \cdot d}{A}$$
$$\epsilon'' = \epsilon' \tan \delta$$

- The model can also be modified by two extra terms to correct the behavior of the function at low frequencies.
- For the real part we have the Maxwell-Wagner term $\frac{\sigma}{\omega^n}$ and for the imaginary part we have a term depending on the conductivity $\frac{\sigma}{\epsilon_0 \omega^n}$

Area measurement



- Measurement of the area was done using the program "Image J"
- Using ruler for estimating length scale
- Final area is the average of 5 measurements
- $\bar{A} = 1,569 \times 10^{-6} \pm 3,69 \times 10^{-8}$
- About 2,4% uncertainty.

Uncertainties

$$\Delta C = 0.01C$$

$$\Delta \tan \delta = 0.01 \tan \delta$$

$$\Delta A = \text{standard deviation of five measurements}$$

As for the uncertainties in the dielectric function values they are calculated using the standard error propagation formula for a standard function f :

$$\Delta f = \sqrt{\left(\frac{\partial f}{\partial x_1} \Delta x_1\right)^2 + \left(\frac{\partial f}{\partial x_2} \Delta x_2\right)^2 + \dots}$$

Data Treatment and analysis

Fitting

- Our objective is to fit the experimental values of the dielectric function to the Havriliak-Negami model and if necessary, add extra corrective terms.

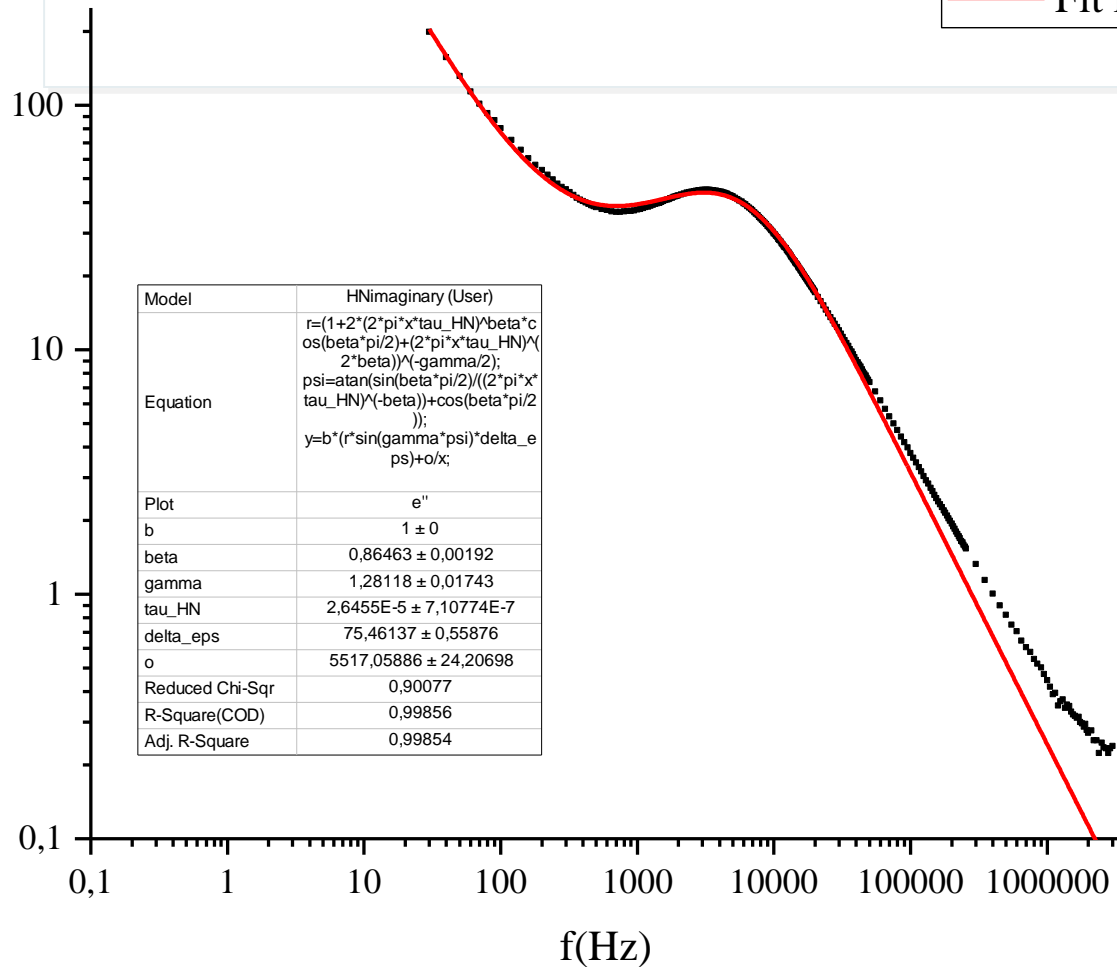


Fits without uncertainties

Imaginary and real part individual fit

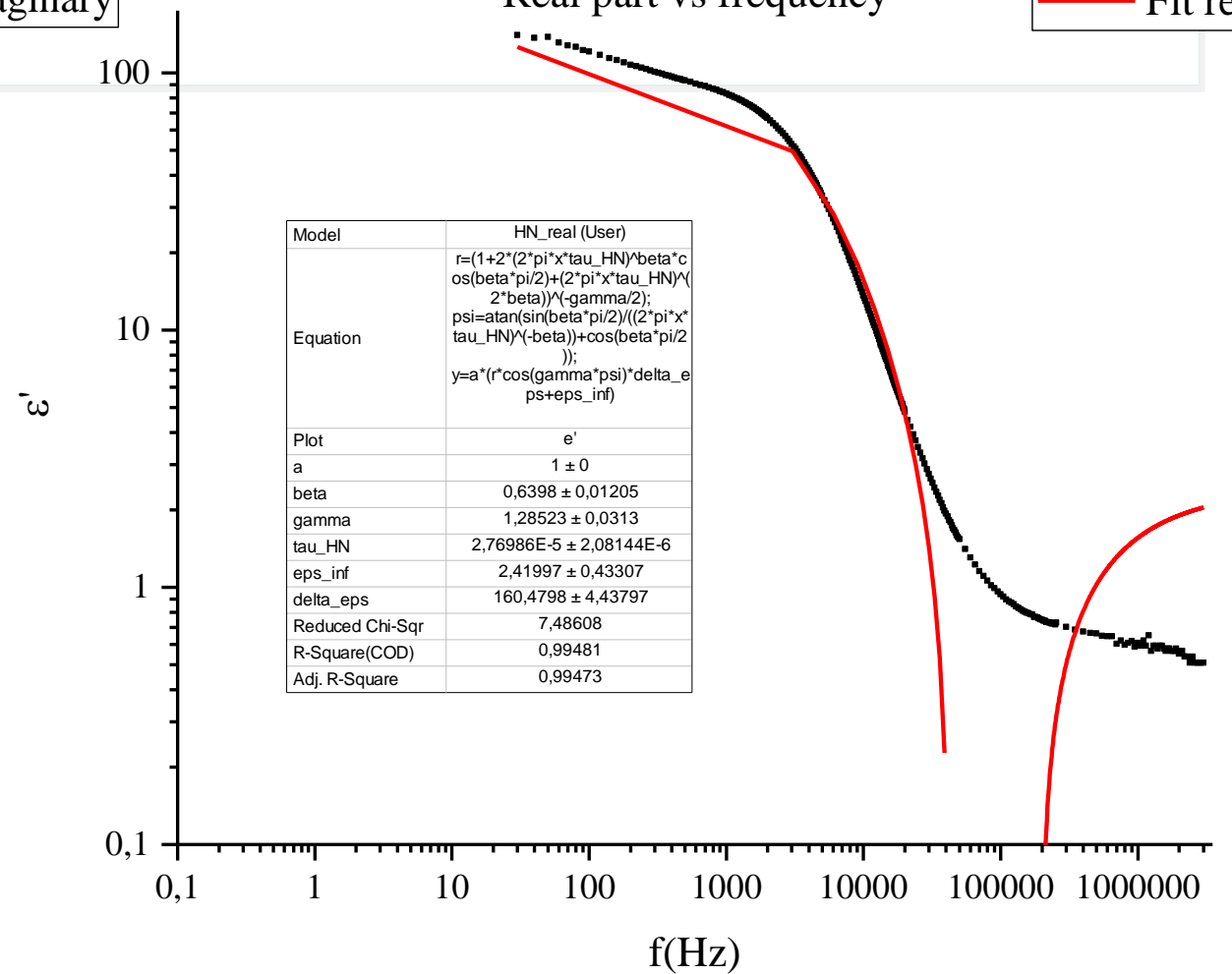
Imaginary part vs frequency

· Imaginary
— Fit imaginary



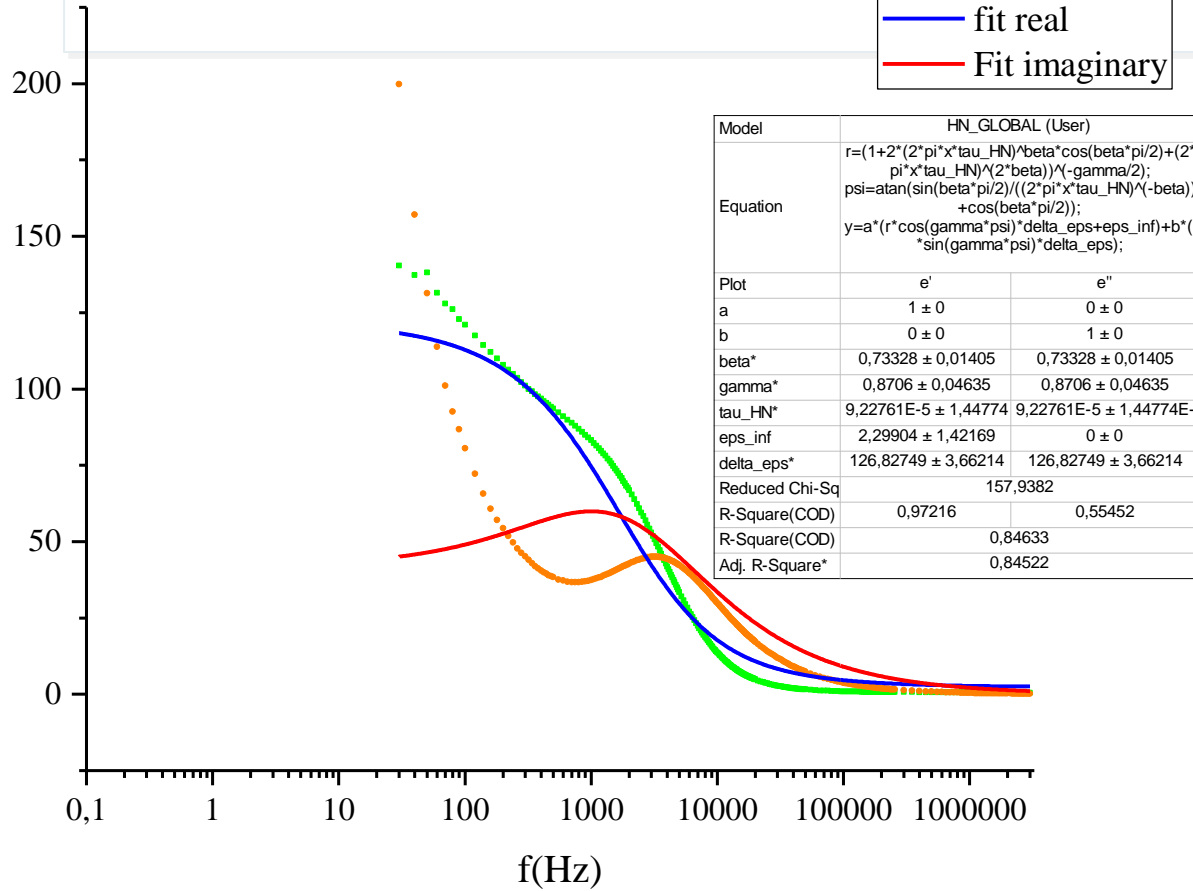
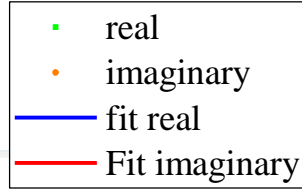
Real part vs frequency

· Real
— Fit real

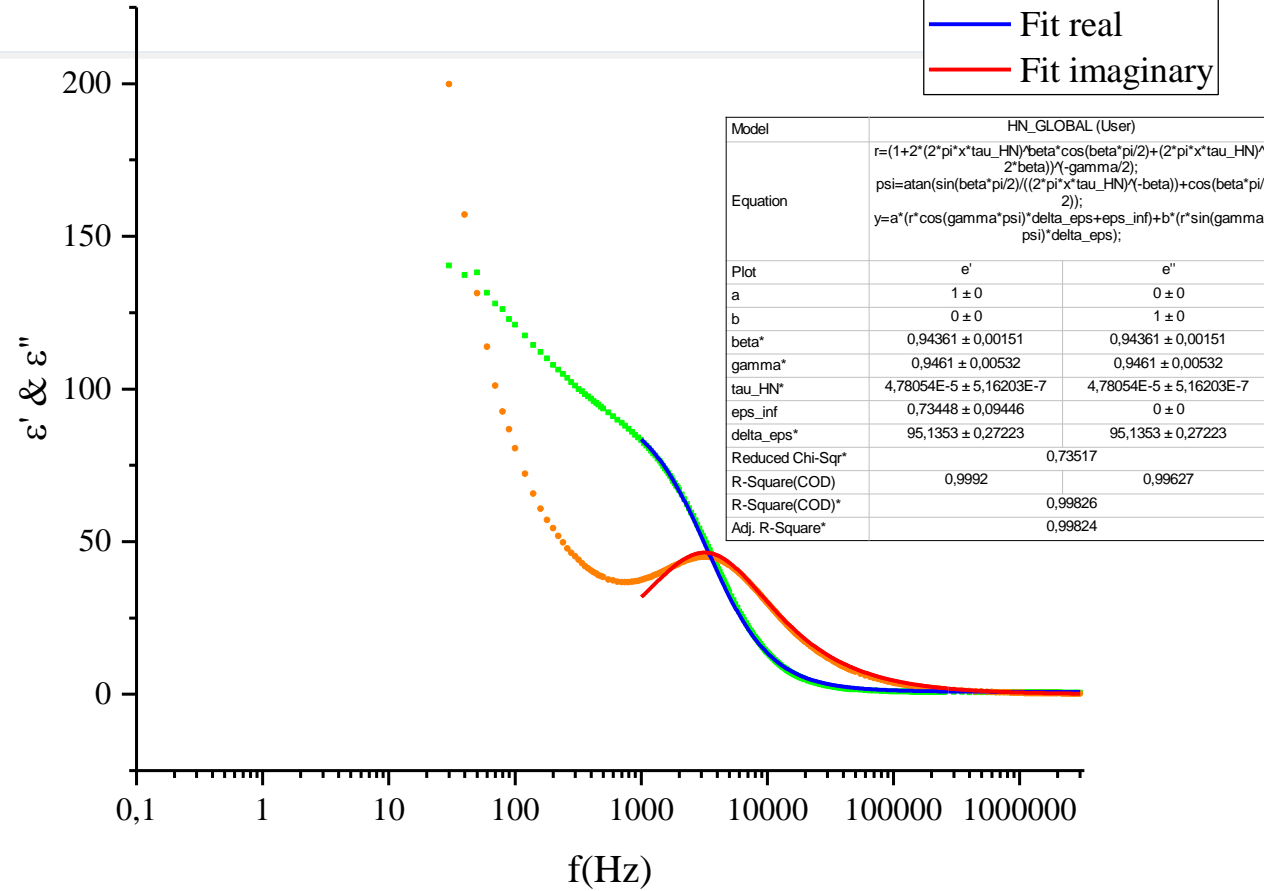
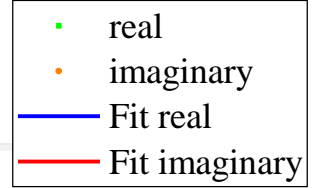


Global fit – No corrections

Real and Imaginary part vs frequency

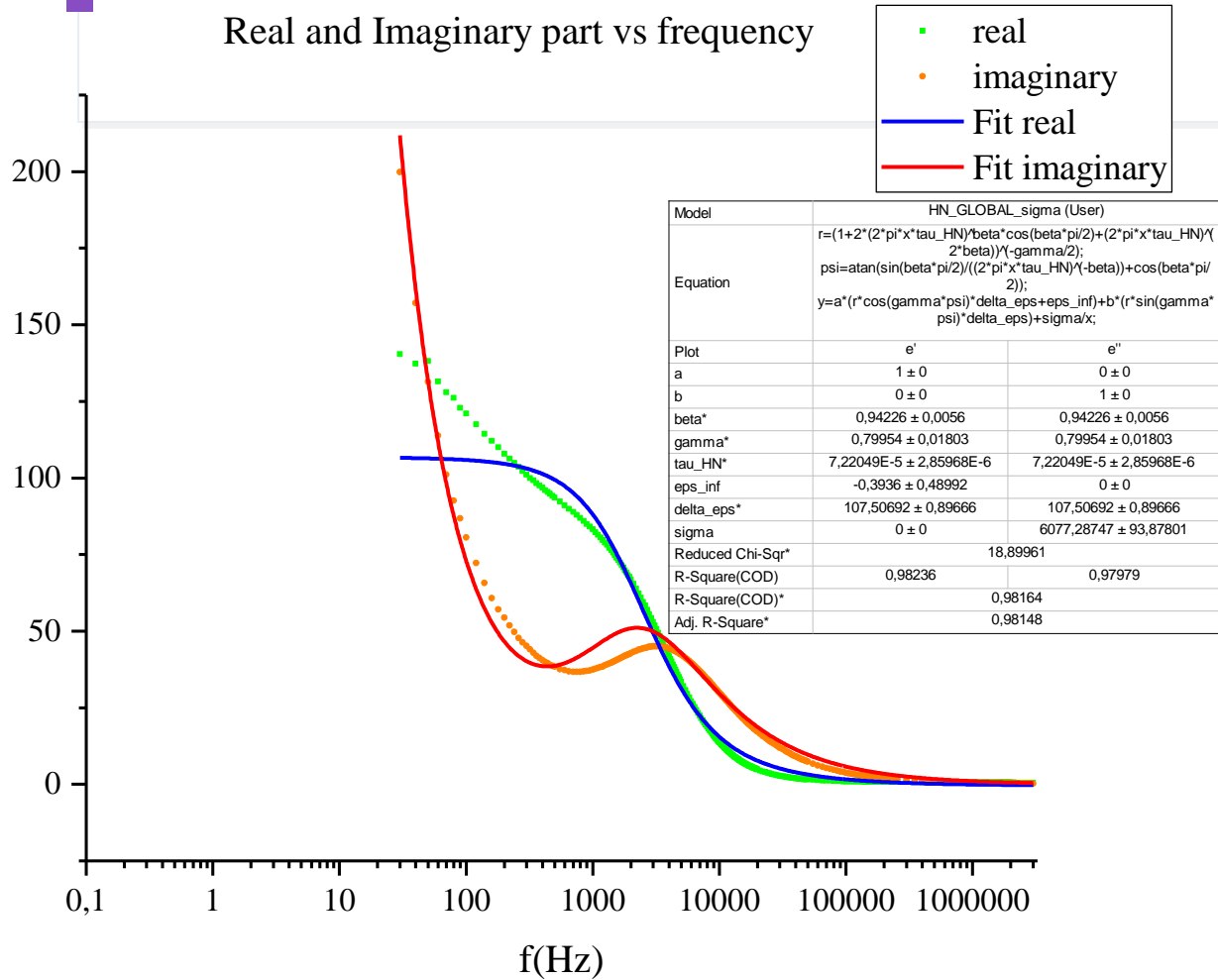


Real and Imaginary part vs frequency

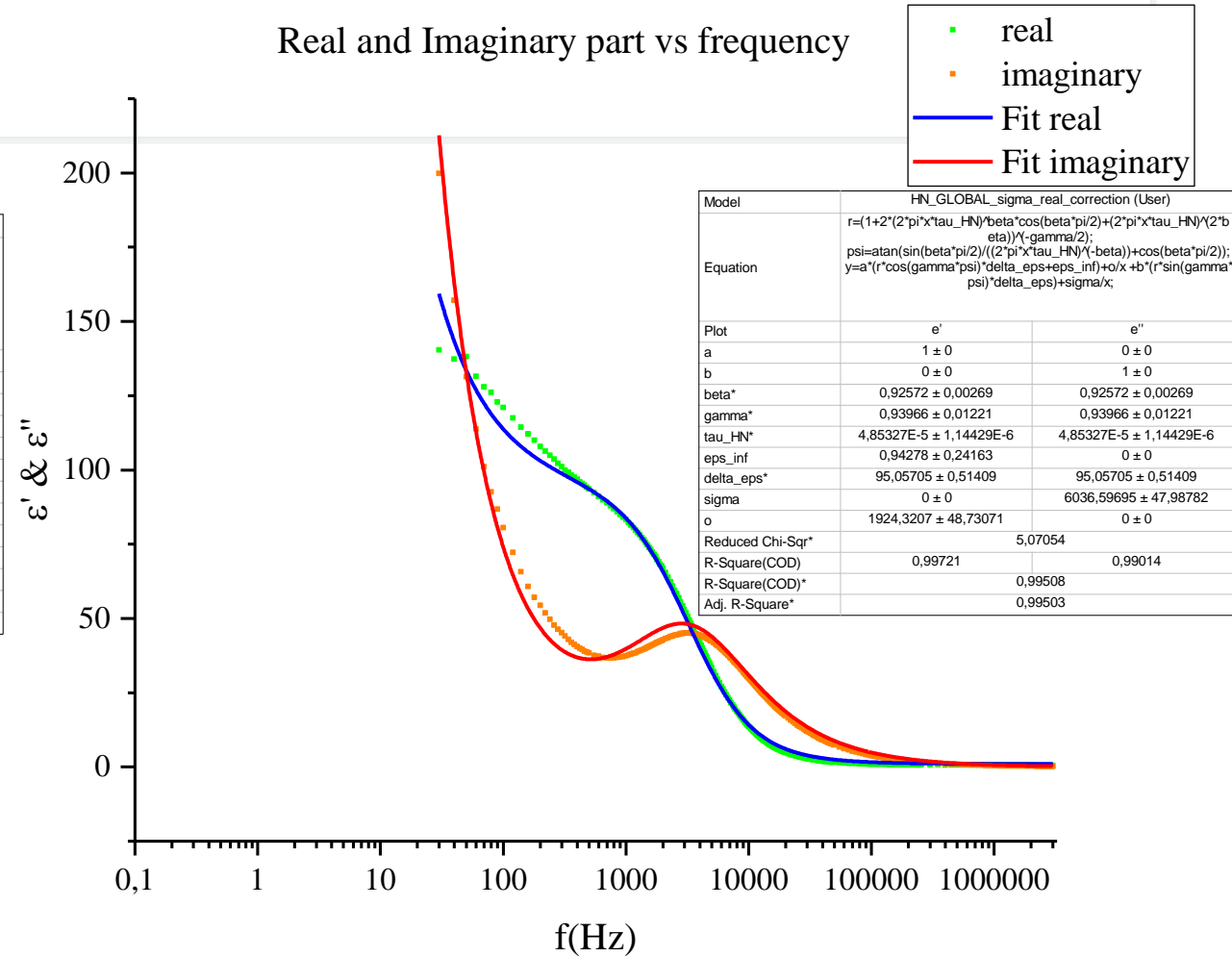


Global fits with real and imaginary corrections

Real and Imaginary part vs frequency

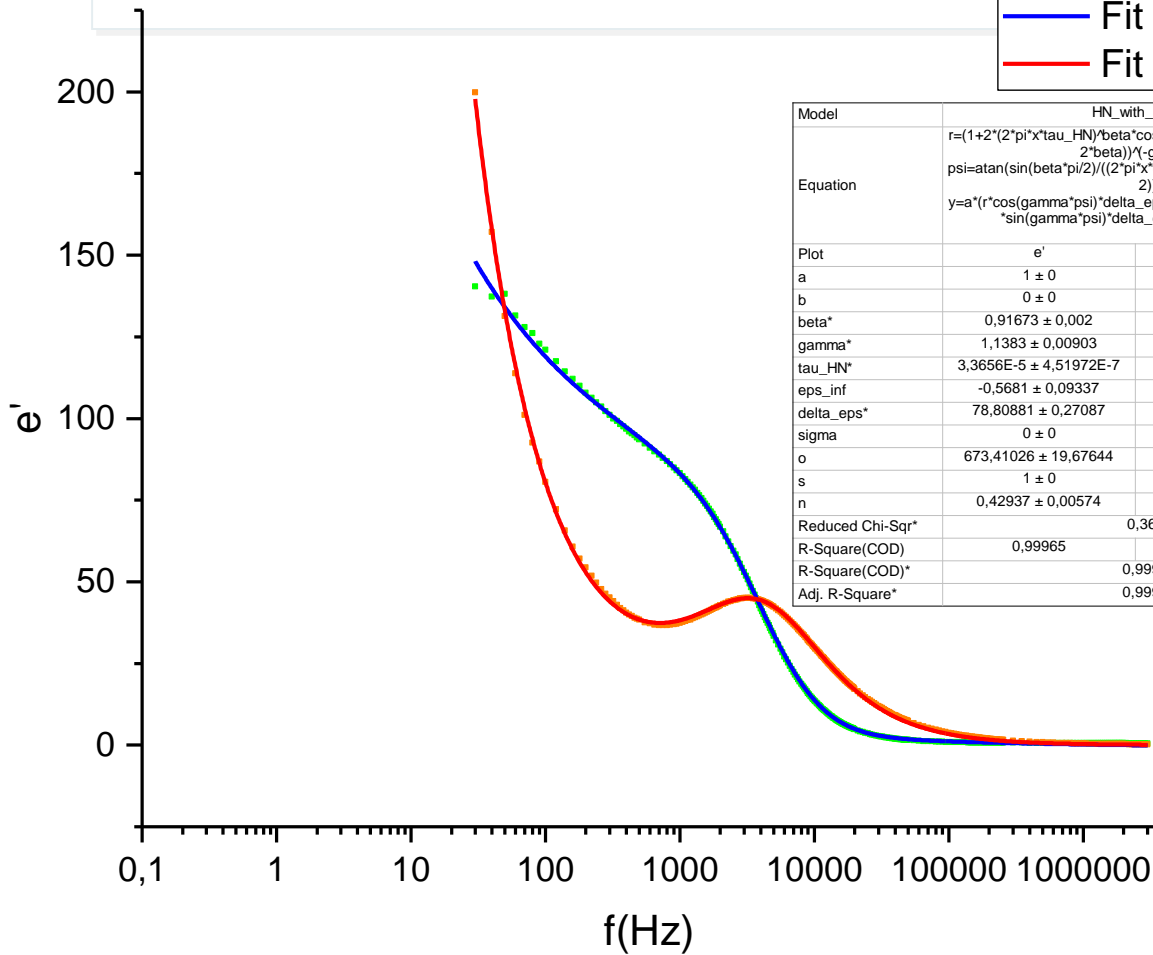


Real and Imaginary part vs frequency



Global fit with corrections with exponents

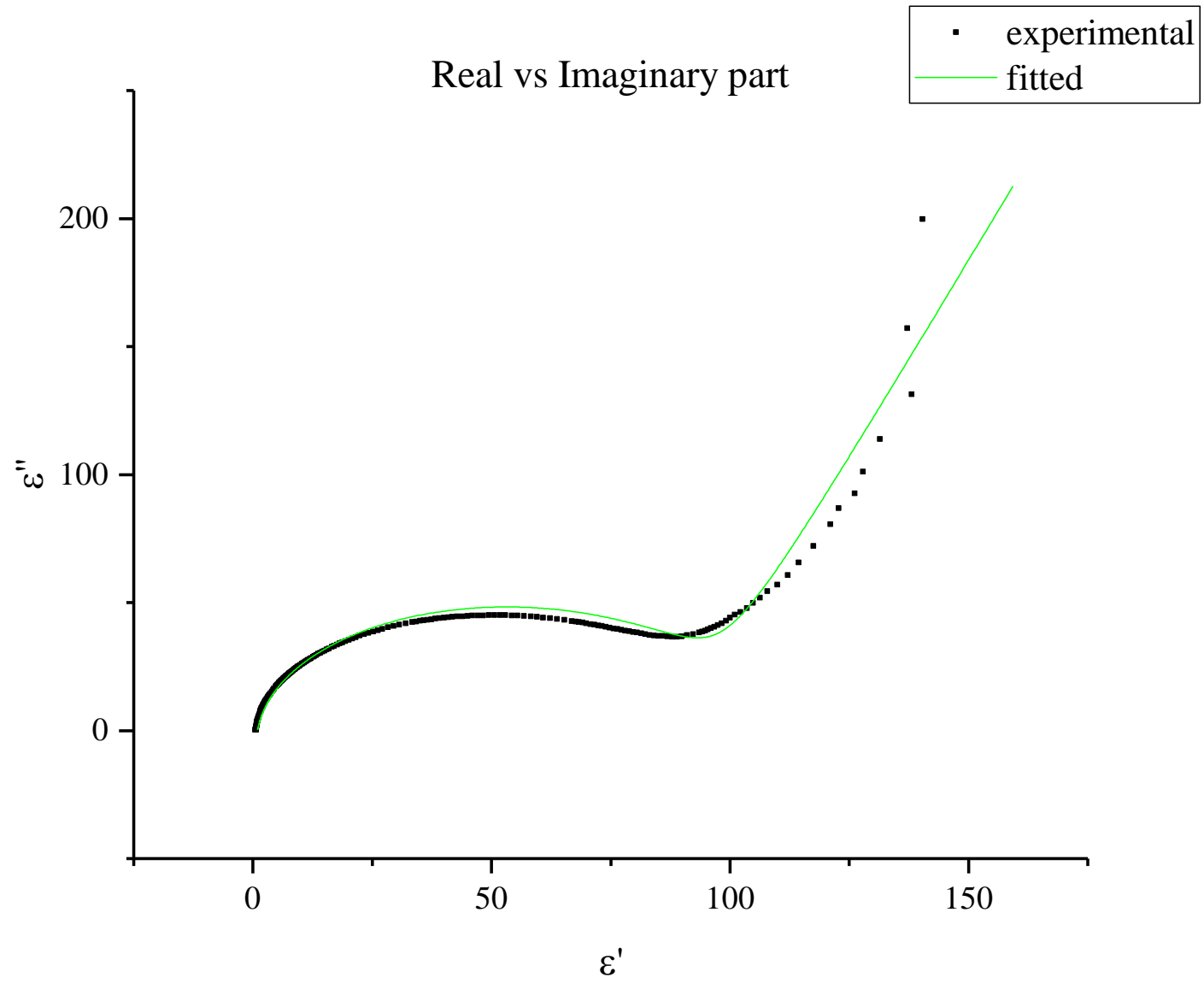
Real and imaginary part vs frequency



- real
- imaginary
- Fit real
- Fit imaginary

Model		
HN_with_S (User)		
Equation	$r=(1+2*(2*\pi*x*\tau_{HN})^\beta*\cos(\beta*\pi/2)+(2*\pi*x*\tau_{HN})^{2*\beta})^{-(\gamma/2)}$ $\psi=\text{atan}(\sin(\beta*\pi/2)/((2*\pi*x*\tau_{HN})^{-\beta})+\cos(\beta*\pi/2));$ $y=a*(r*\cos(\gamma*\psi)*\delta_{\text{eps}}+\epsilon_{\text{inf}})+o/(2*\pi*x)^n +b*(r*\sin(\gamma*\psi)*\delta_{\text{eps}}+\sigma/(2*\pi*x)^s);$	
Plot	e'	e''
a	1 ± 0	0 ± 0
b	0 ± 0	1 ± 0
beta*	0,91673 ± 0,002	0,91673 ± 0,002
gamma*	1,1383 ± 0,00903	1,1383 ± 0,00903
tau_HN*	3,3656E-5 ± 4,51972E-7	3,3656E-5 ± 4,51972E-7
eps_inf	-0,5681 ± 0,09337	0 ± 0
delta_eps*	78,80881 ± 0,27087	78,80881 ± 0,27087
sigma	0 ± 0	16261,66446 ± 448,31126
o	673,41026 ± 19,67644	0 ± 0
s	1 ± 0	0,85394 ± 0,00528
n	0,42937 ± 0,00574	1 ± 0
Reduced Chi-Sqr*	0,3619	
R-Square(COD)	0,99965	0,99965
R-Square(COD)*	0,99965	
Adj. R-Square*	0,99965	

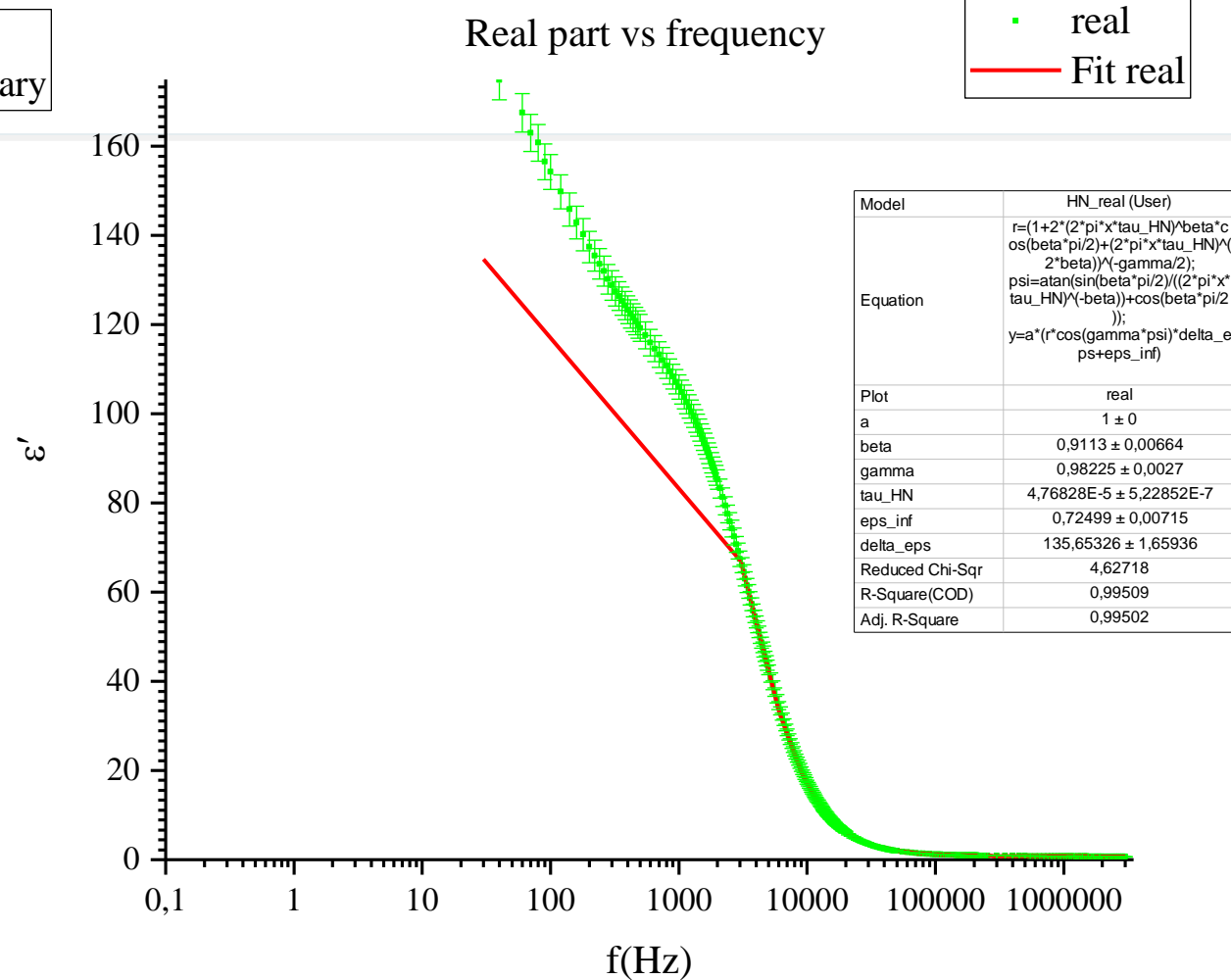
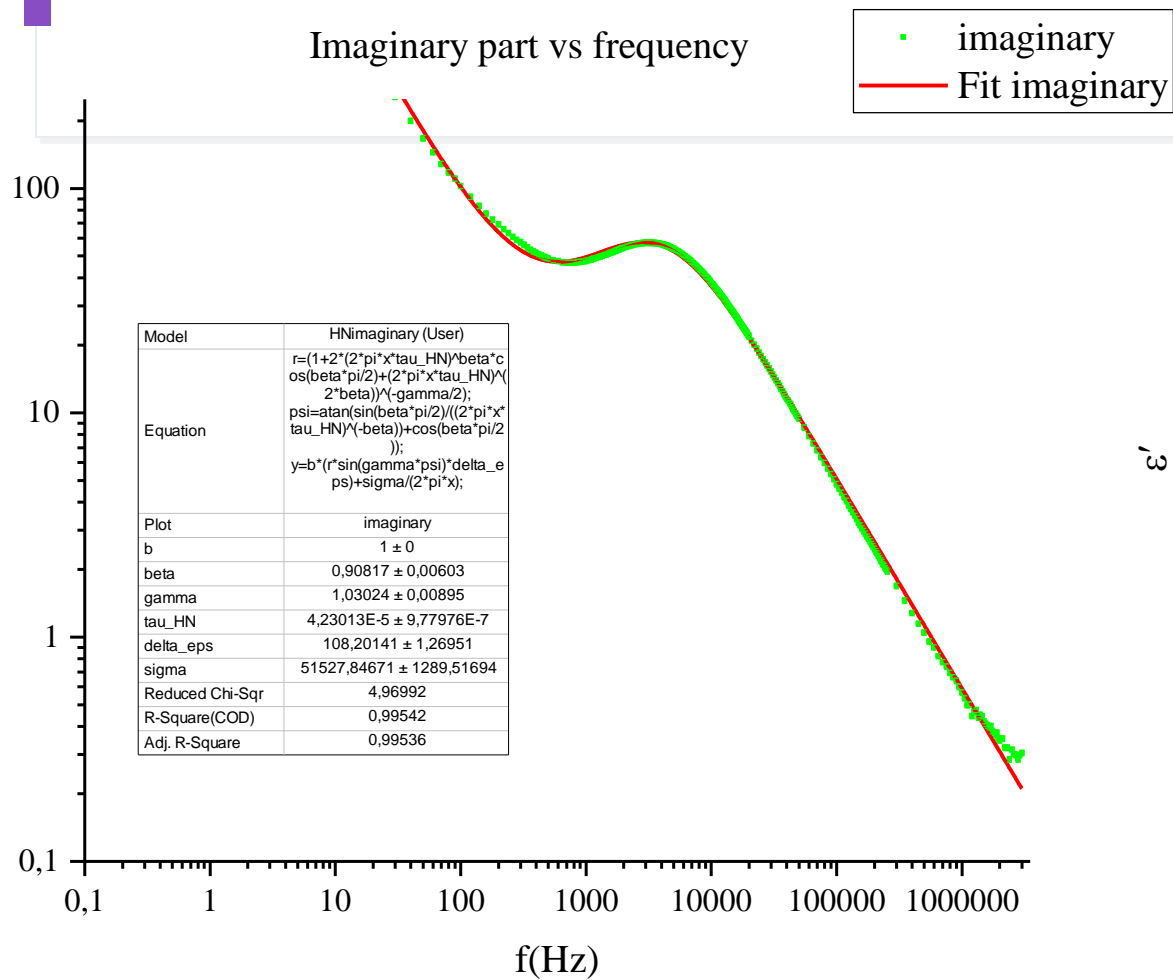
Model		
HN_with_S (User)		
Equation	$r=(1+2*(2*\pi*x*\tau_{HN})^\beta*\cos(\beta*\pi/2)+(2*\pi*x*\tau_{HN})^{2*\beta})^{-(\gamma/2)}$ $\psi=\text{atan}(\sin(\beta*\pi/2)/((2*\pi*x*\tau_{HN})^{-\beta})+\cos(\beta*\pi/2));$ $y=a*(r*\cos(\gamma*\psi)*\delta_{\text{eps}}+\epsilon_{\text{inf}})+o/(2*\pi*x)^n +b*(r*\sin(\gamma*\psi)*\delta_{\text{eps}}+\sigma/(2*\pi*x)^s);$	
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sigma	0 ± 0	16261,66446 ± 448,31126
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R-Square(COD)	0,99965	0,99965
R-Square(COD)*	0,99965	
Adj. R-Square*	0,99965	





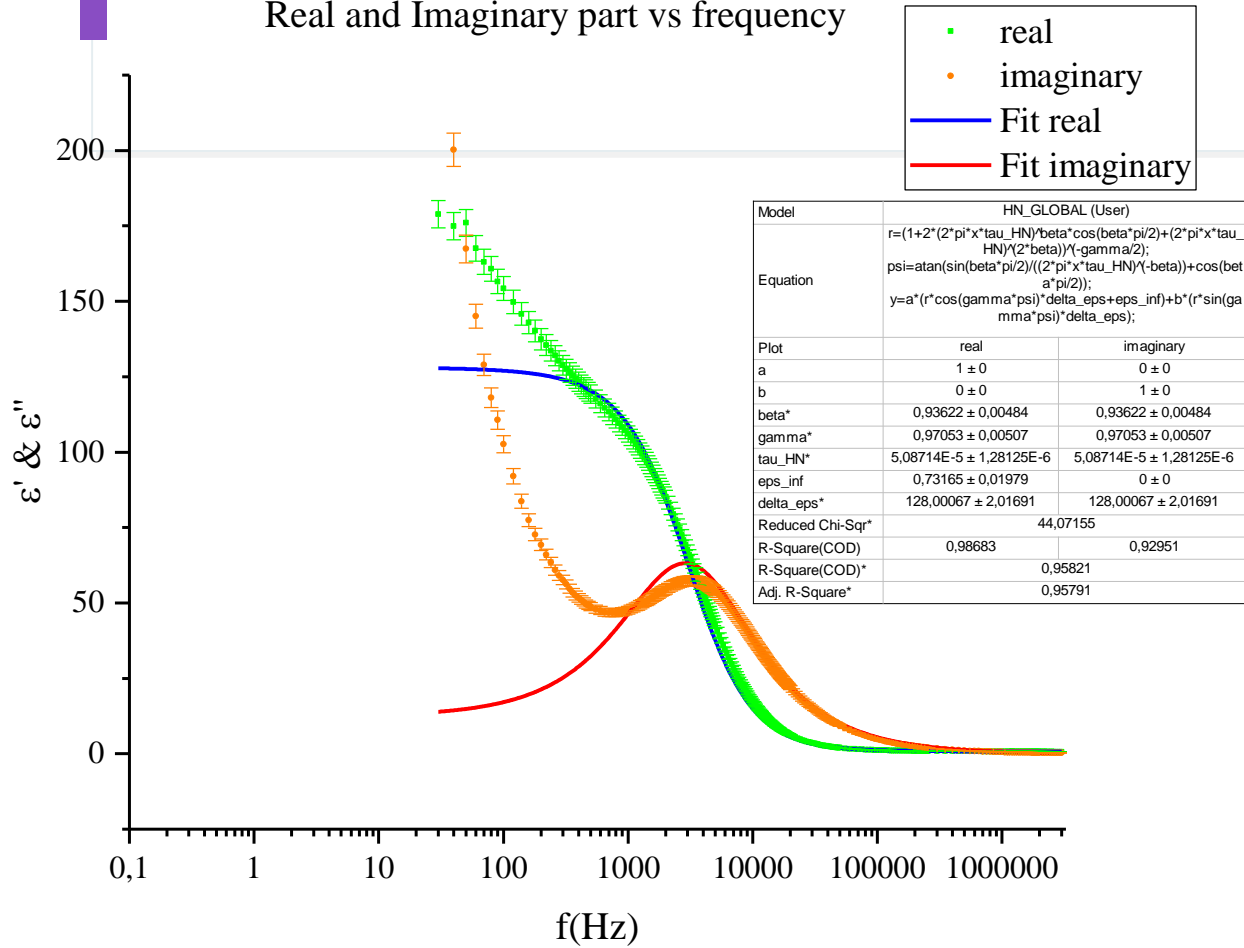
Fits with uncertainties

Imaginary and real part individual fit

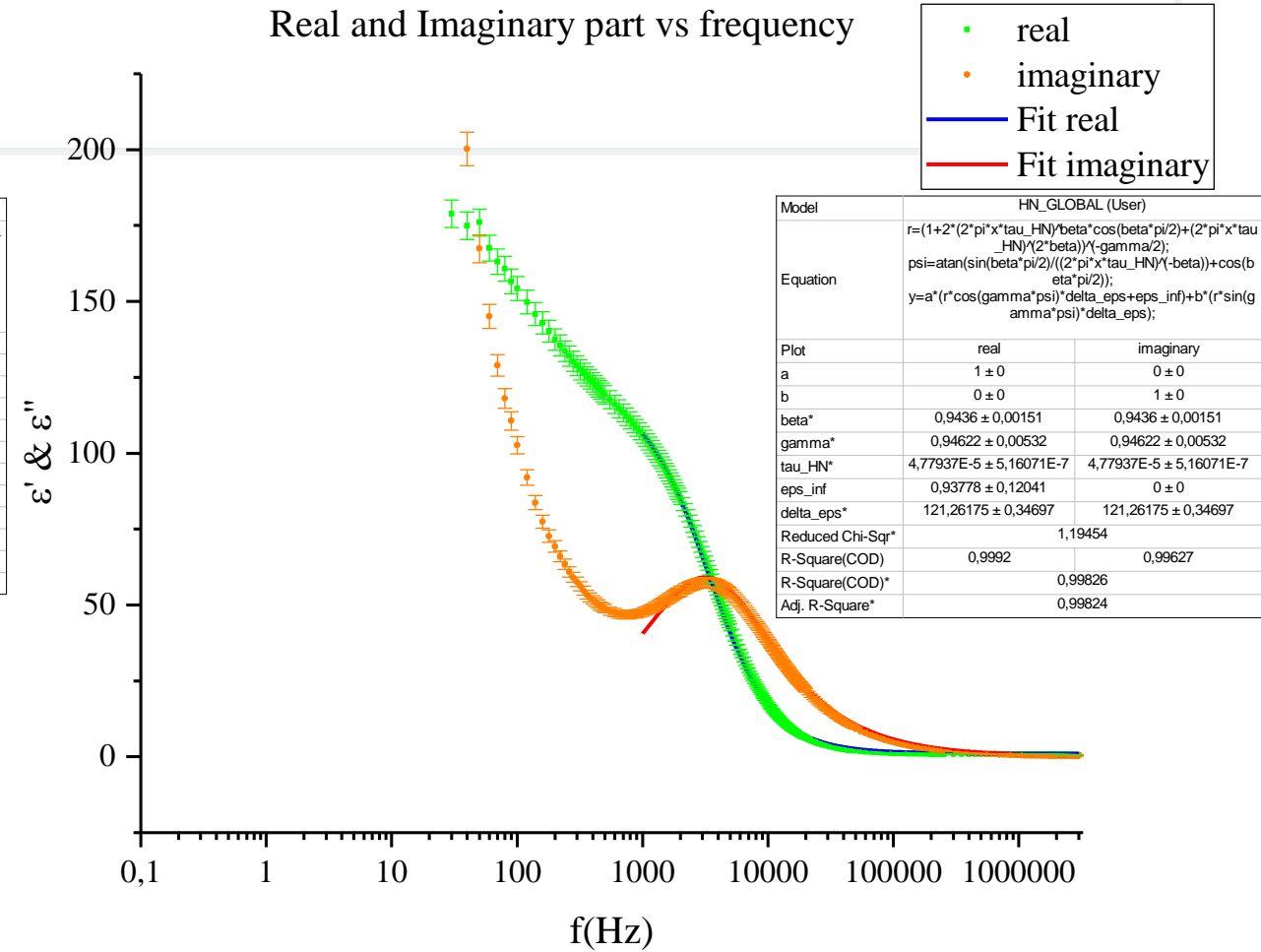


Global fit – No corrections

Real and Imaginary part vs frequency



Real and Imaginary part vs frequency



Global fits with real and imaginary corrections

Real and Imaginary part vs frequency

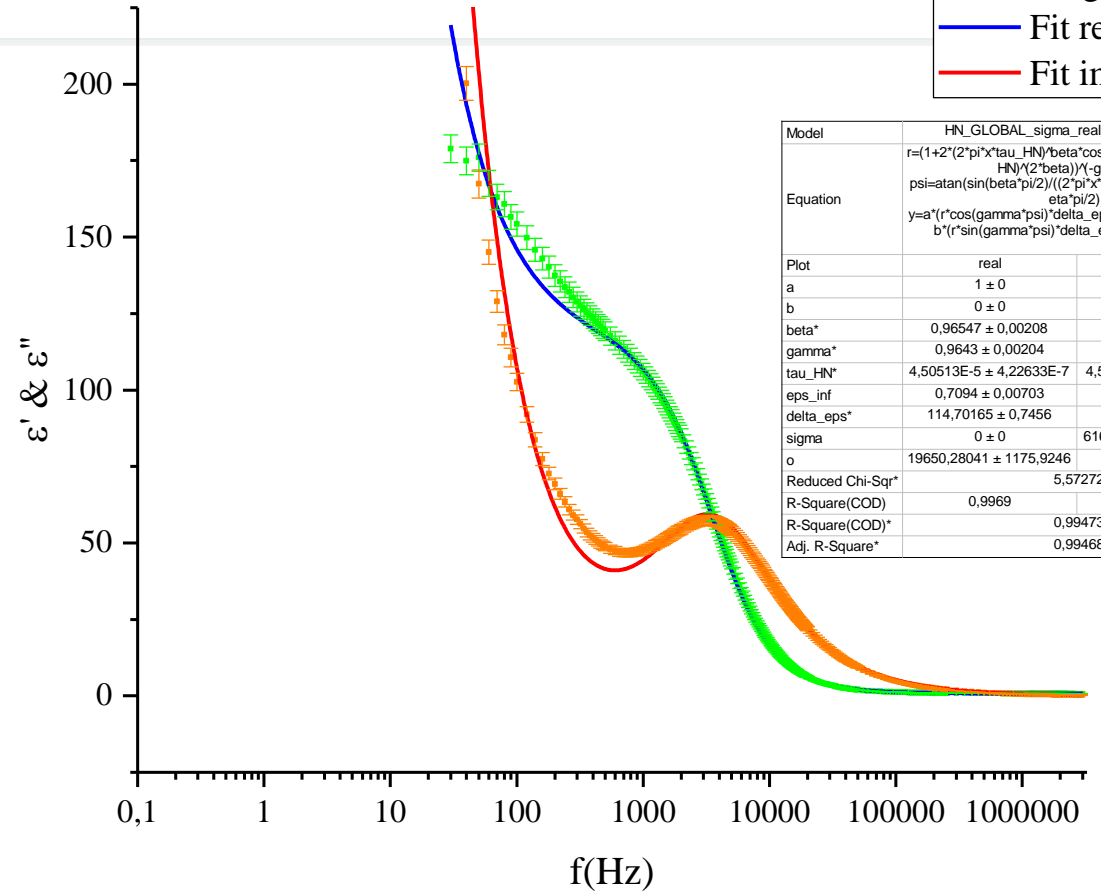
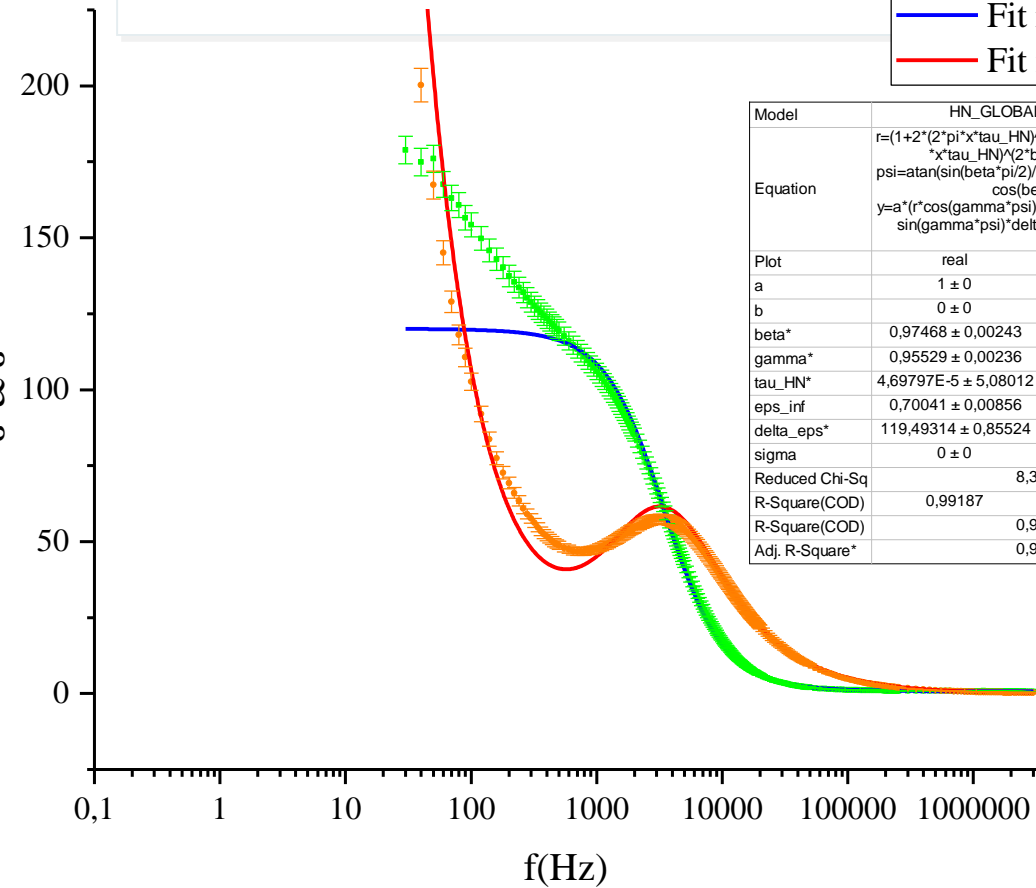
- real
- imaginary
- Fit real
- Fit imaginary

Model	HN_GLOBAL_sigma (User)	
Equation	$r=(1+2*(2*\pi*x*\tau_{HN})^\beta \cos(\beta*\pi/2)+(2*\pi*x*\tau_{HN})^{2*\beta})^{-(\gamma/2)}$ $\psi=\text{atan}(\sin(\beta*\pi/2)/((2*\pi*x*\tau_{HN})^{-(\beta-1)}+\cos(\beta*\pi/2)))$ $y=a*(r*\cos(\gamma*\psi)^{\delta*\epsilon+\epsilon_{inf}})+b*(r*\sin(\gamma*\psi)^{\delta*\epsilon+\epsilon_{inf}})+\sigma/(2*\pi*x)$	
Plot	real	imaginary
a	1 ± 0	0 ± 0
b	0 ± 0	1 ± 0
beta*	0,97468 ± 0,00243	0,97468 ± 0,00243
gamma*	0,95529 ± 0,00236	0,95529 ± 0,00236
tau_HN*	4,69797E-5 ± 5,08012E-5	4,69797E-5 ± 5,08012E-5
eps_inf	0,70041 ± 0,00856	0 ± 0
delta_eps*	119,49314 ± 0,85524	119,49314 ± 0,85524
sigma	0 ± 0	61944,06208 ± 1274,87
Reduced Chi-Sq	8,38232	
R-Square(COD)	0,99187	0,9915
R-Square(COD)*	0,99207	
Adj. R-Square*	0,99199	

Real and Imaginary part vs frequency

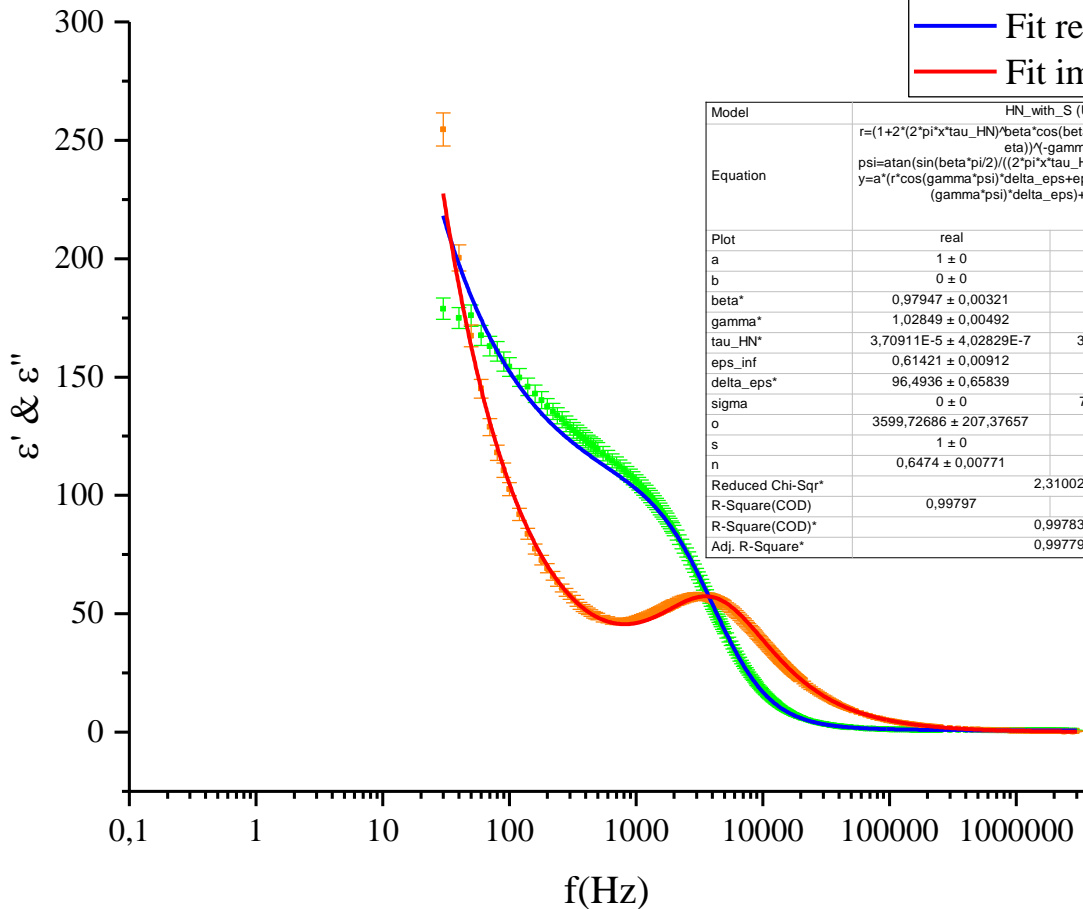
- real
- imaginary
- Fit real
- Fit imaginary

Model	HN_GLOBAL_sigma_real_correction (User)	
Equation	$r=(1+2*(2*\pi*x*\tau_{HN})^\beta \cos(\beta*\pi/2)+(2*\pi*x*\tau_{HN})^{2*\beta})^{-(\gamma/2)}$ $\psi=\text{atan}(\sin(\beta*\pi/2)/((2*\pi*x*\tau_{HN})^{-(\beta-1)}+\cos(\beta*\pi/2)))$ $y=a*(r*\cos(\gamma*\psi)^{\delta*\epsilon+\epsilon_{inf}})+o/(2*\pi*x)+b*(r*\sin(\gamma*\psi)^{\delta*\epsilon+\epsilon_{inf}})+\sigma/(2*\pi*x)$	
Plot	real	imaginary
a	1 ± 0	0 ± 0
b	0 ± 0	1 ± 0
beta*	0,96547 ± 0,00208	0,96547 ± 0,00208
gamma*	0,9643 ± 0,00204	0,9643 ± 0,00204
tau_HN*	4,50513E-5 ± 4,22633E-7	4,50513E-5 ± 4,22633E-7
eps_inf	0,7094 ± 0,00703	0 ± 0
delta_eps*	114,70165 ± 0,7456	114,70165 ± 0,7456
sigma	0 ± 0	61667,12656 ± 1035,3773
o	19650,28041 ± 1175,9246	0 ± 0
Reduced Chi-Sqr*	5,57272	
R-Square(COD)	0,9969	0,99237
R-Square(COD)*	0,99473	
Adj. R-Square*	0,99468	



Global fit with corrections with exponents

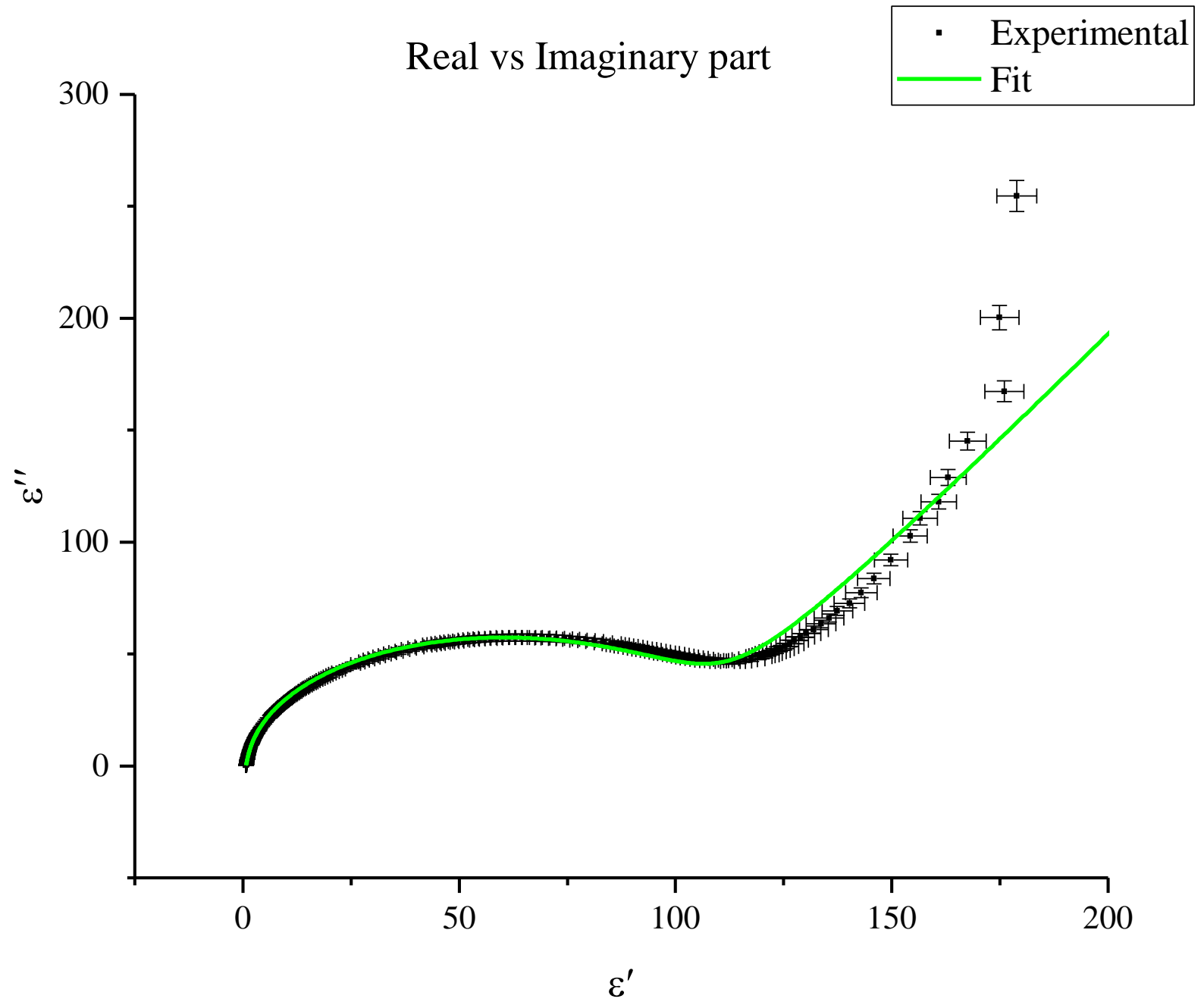
Real and Imaginary part vs frequency



• real
• imaginary
— Fit real
— Fit imaginary

Model		
Model	HN_with_S (User)	
Equation	$r=(1+2^{*(2*\pi*x*tau_HN)^beta*\cos(beta*\pi/2)}+(2*\pi*x*tau_HN)^{2*b*eta})^{(-gamma/2)}$ $psi=atan(\sin(beta*\pi/2)/((2*\pi*x*tau_HN)^{-beta})+\cos(beta*\pi/2))$ $y=a*(r*\cos(gamma*psi)*delta_eps+eps_inf)+o/(2*\pi*x)^n +b*(r*\sin(gamma*psi)*delta_eps)+sigma/(2*\pi*x)^s$	
Plot	real	imaginary
a	1 ± 0	0 ± 0
b	0 ± 0	1 ± 0
beta*	0,97947 ± 0,00321	0,97947 ± 0,00321
gamma*	1,02849 ± 0,00492	1,02849 ± 0,00492
tau_HN*	3,70911E-5 ± 4,02829E-7	3,70911E-5 ± 4,02829E-7
eps_inf	0,61421 ± 0,00912	0 ± 0
delta_eps*	96,4936 ± 0,65839	96,4936 ± 0,65839
sigma	0 ± 0	7680,61479 ± 248,80417
o	3599,72686 ± 207,37657	0 ± 0
s	1 ± 0	0,67502 ± 0,00442
n	0,6474 ± 0,00771	1 ± 0
Reduced Chi-Sqr*	2,31002	
R-Square(COD)	0,99797	0,9975
R-Square(COD)*	0,99783	
Adj. R-Square*	0,99779	

Model		
Model	HN_with_S (User)	
Equation	$r=(1+2^{*(2*\pi*x*tau_HN)^beta*\cos(beta*\pi/2)}+(2*\pi*x*tau_HN)^{2*b*eta})^{(-gamma/2)}$ $psi=atan(\sin(beta*\pi/2)/((2*\pi*x*tau_HN)^{-beta})+\cos(beta*\pi/2))$ $y=a*(r*\cos(gamma*psi)*delta_eps+eps_inf)+o/(2*\pi*x)^n +b*(r*\sin(gamma*psi)*delta_eps)+sigma/(2*\pi*x)^s$	
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s	1 ± 0	0,67502 ± 0,00442
n	0,6474 ± 0,00771	1 ± 0
Reduced Chi-Sqr*	2,31002	
R-Square(COD)	0,99797	0,9975
R-Square(COD)*	0,99783	
Adj. R-Square*	0,99779	



Parameter comparison

Fits Parameters	without uncertainties and exponents	with uncertainties but without exponents	without uncertainties and with exponents	with uncertainties and exponents
$\sigma(\Omega m)^{-1}$	$5,38 \times 10^{-8}$ $\pm 8,31 \times 10^{-10}$	$5,48 \times 10^{-7}$ $\pm 1,13 \times 10^{-8}$	$1,43 \times 10^{-7}$ $\pm 3,97 \times 10^{-9}$	$6,80 \times 10^{-8}$ $\pm 2,20 \times 10^{-9}$
ϵ_{∞}	$-0,39 \pm 0,49$	$0,70 \pm 0,01$	$-0,57 \pm 0,09$	$0,61 \pm 0,01$
β	$0,73 \pm 0,01$	$0,97 \pm 0,01$	$0,92 \pm 0,002$	$0,98 \pm 0,01$
τ_{HN}	$(9,22 + 1,45)$ $\times 10^{-5}$	$4,70 \times 10^{-5}$ $\pm 5,08 \times 10^{-7}$	$3,37 \times 10^{-5}$ $\pm 4,51 \times 10^{-7}$	$3,71 \times 10^{-5}$ $\pm 4,03 \times 10^{-7}$
$\Delta\epsilon$	$126,83 \pm 3,66$	$119,49 \pm 0,86$	$78,81 \pm 0,27$	$96,49 \pm 0,66$
\mathcal{O}	-----	-----	$673,41 \pm 19,68$	$3599,73 \pm 207,38$
s	-----	-----	$0,85 \pm 0,01$	$0,68 \pm 0,01$
n	-----	-----	$0,43 \pm 0,01$	$0,65 \pm 0,01$

Conclusions



Comparison of the fits

- Adding the Maxwell-Wagner and conductivity terms improved the fit to the data in the lower frequencies range.
- Comparing with the independent fit, the global fit has a better fit as indicated by the chi-squared.
- The global fit real part vs. frequency approaches the experimental data without uncertainties better than the data with uncertainty.

Comparison of the fits

- The global fit without uncertainties has a smaller chi-squared than with uncertainties, because in the latter the real part fit begins to diverge at lower frequencies.
- It's might be due to the different weights of the different points that make the fit converge to another solution.

Possible Improvements

- Improvements in area measurements (higher resolution pictures for example)
- C and $\tan \delta$ error only estimated
 - Check manufacturer information of measuring devices
- Deviation of fit and data in the real part (low frequency range)
 - Add different terms to the equation? Would another model be more accurate for our sample?